

DS90CF561/DS90CF562 LVDS 18-Bit Color Flat Panel Display (FPD) Link

General Description

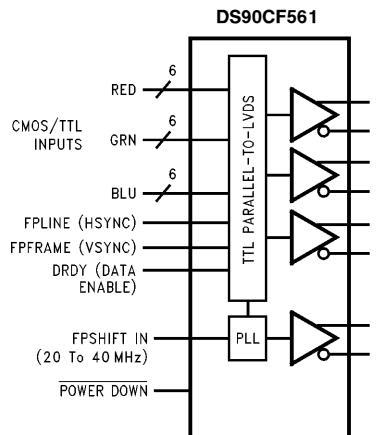
The DS90CF561 transmitter converts 21 bits of CMOS/TTL data into three LVDS (Low Voltage Differential Signaling) data streams. A phase-locked transmit clock is transmitted in parallel with the data streams over a fourth LVDS link. Every cycle of the transmit clock 21 bits of input data are sampled and transmitted. The DS90CF562 receiver converts the LVDS data streams back into 21 bits of CMOS/TTL data. At a transmit clock frequency of 40 MHz, 18 bits of RGB data and 3 bits of LCD timing and control data (FPLINE, FPFRAME, DRDY) are transmitted at a rate of 280 Mbps per LVDS data channel. Using a 40 MHz clock, the data throughput is 105 Megabytes per second. These devices are offered with falling edge data strobes for convenient interface with a variety of graphics and LCD panel controllers.

This chipset is an ideal means to solve EMI and cable size problems associated with wide, high speed TTL interfaces.

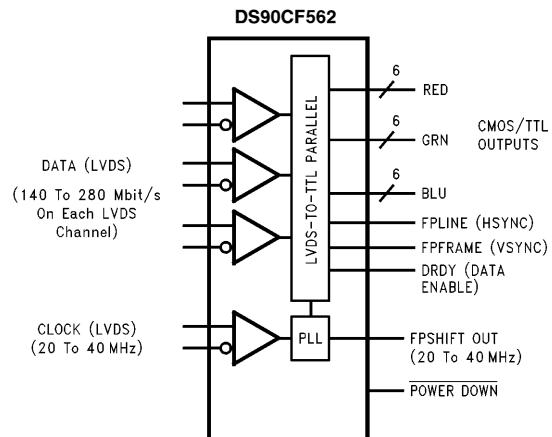
Features

- Up to 105 Megabyte/sec bandwidth
- Narrow bus reduces cable size
- 345 mV swing LVDS devices for low EMI
- Low power CMOS design
- Power down mode
- PLL requires no external components
- Low profile 48-lead TSSOP package
- Falling edge data strobe
- Compatible with TIA/EIA-644 LVDS standard

Block Diagrams



Order Number DS90CF561MTD
See NS Package Number MTD48

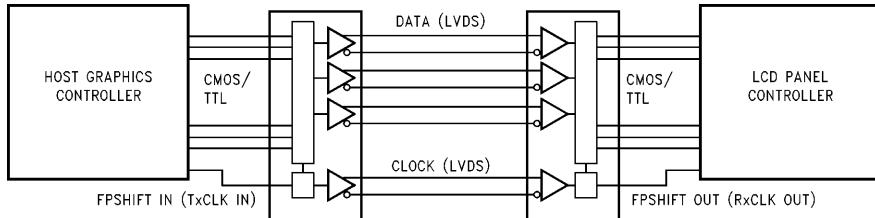


Order Number DS90CF562MTD
See NS Package Number MTD48

TL/F/12485-1

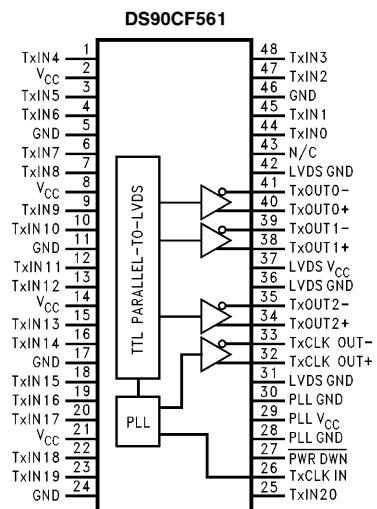
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Application

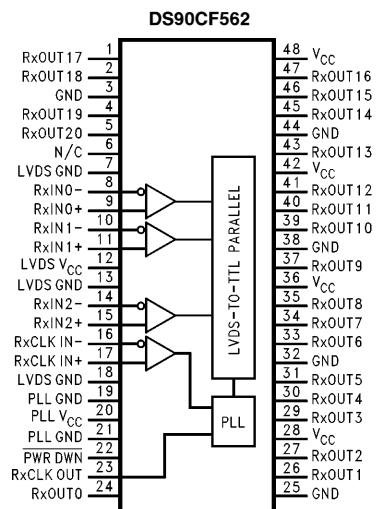


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Connection Diagrams



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Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.3V to +6V
CMOS/TTL Input Voltage	-0.3V to (V_{CC} + 0.3V)
CMOS/TTL Output Voltage	-0.3V to (V_{CC} + 0.3V)
LVDS Receiver Input Voltage	-0.3V to (V_{CC} + 0.3V)
LVDS Driver Output Voltage	-0.3V to (V_{CC} + 0.3V)
LVDS Output Short Circuit Duration	continuous
Junction Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering, 4 sec.)	+260°C

Maximum Power Dissipation @ +25°C

MTD48 (TSSOP) Package:	
DS90CF561	1.98W
DS90CF562	1.89W

Package Derating: DS90CF561	16 mW/°C above +25°C
DS90CF562	15 mW/°C above +25°C

This device does not meet 2000V ESD rating (Note 4).

Recommended Operating Conditions

	Min	Nom	Max	Units
Supply Voltage (V_{CC})	4.5	5.0	5.5	V
Operating Free Air Temperature (T_A)	-10	+25	+70	°C
Receiver Input Range	0		2.4	V

Electrical Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Units
CMOS/TTL DC SPECIFICATIONS						
V_{IH}	High Level Input Voltage		2.0		V_{CC}	V
V_{IL}	Low Level Input Voltage		GND		0.8	V
V_{OH}	High Level Output Voltage	$I_{OH} = -0.4$ mA	3.8	4.9		V
V_{OL}	Low Level Output Voltage	$I_{OL} = 2$ mA		0.1	0.3	V
V_{CL}	Input Clamp Voltage	$I_{CL} = -18$ mA		-0.79	-1.5	V
I_{IN}	Input Current	$V_{IN} = V_{CC}$, GND, 2.5V or 0.4V		± 5.1	± 10	μA
I_{OS}	Output Short Circuit Current	$V_{OUT} = 0$ V			-120	mA

LVDS DRIVER DC SPECIFICATIONS

V_{OD}	Differential Output Voltage	$R_L = 100\Omega$	250	290	450	mV
ΔV_{OD}	Change in V_{OD} between Complimentary Output States				35	mV
V_{CM}	Common Mode Voltage		1.1	1.25	1.375	V
ΔV_{CM}	Change in V_{CM} between Complimentary Output States				35	V
V_{OH}	High Level Output Voltage			1.3	1.6	V
V_{OL}	Low Level Output Voltage		0.9	1.07		V
I_{OS}	Output Short Circuit Current	$V_{OUT} = 0$ V, $R_L = 100\Omega$		-2.9	-5	mA
I_{OZ}	Output TRI-STATE® Current	$Power Down = 0$ V, $V_{OUT} = 0$ V or V_{CC}		± 1	± 10	μA

LVDS RECEIVER DC SPECIFICATIONS

V_{TH}	Differential Input High Threshold	$V_{CM} = +1.2$ V			+100	mV
V_{TL}	Differential Input Low Threshold		-100			mV
I_{IN}	Input Current	$V_{IN} = +2.4$ V	$V_{CC} = 5.5$ V		± 10	μA
		$V_{IN} = 0$ V			± 10	μA

Note 1: "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. They are not meant to imply that the device should be operated at these limits. The tables of "Electrical Characteristics" specify conditions for device operation.

Note 2: Typical values are given for $V_{CC} = 5.0$ V and $T_A = +25$ °C.

Note 3: Current into device pins is defined as positive. Current out of device pins is defined as negative. Voltages are referenced to ground unless otherwise specified (except V_{OD} and ΔV_{OD}).

Note 4: ESD Rating: HBM (1.5 kΩ, 100 pF)

PLL $V_{CC} \geq 1000$ V

All other pins ≥ 2000 V

EIAJ (0Ω, 200 pF) ≥ 150 V

Electrical Characteristics (Continued)

Over recommended operating supply and temperature ranges unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Units
TRANSMITTER SUPPLY CURRENT						
I _{CCTW}	Transmitter Supply Current, Worst Case	$R_L = 100\Omega$, $C_L = 5 \text{ pF}$, Worst Case Pattern (<i>Figures 1, 3</i>)	f = 32.5 MHz	34	46	mA
			f = 37.5 MHz	36	48	mA
I _{CCTG}	Transmitter Supply Current, 16 Grayscale	$R_L = 100\Omega$, $C_L = 5 \text{ pF}$, Grayscale Pattern (<i>Figures 2, 3</i>)	f = 32.5 MHz	27	42	mA
			f = 37.5 MHz	28	43	mA
I _{CCTZ}	Transmitter Supply Current, Power Down	Power Down = Low		1	10	μA
RECEIVER SUPPLY CURRENT						
I _{CCRW}	Receiver Supply Current, Worst Case	$C_L = 8 \text{ pF}$, Worst Case Pattern (<i>Figures 1, 4</i>)	f = 32.5 MHz	55	75	mA
			f = 37.5 MHz	60	80	mA
I _{CCRG}	Receiver Supply Current, 16 Grayscale	$C_L = 8 \text{ pF}$, 16 Grayscale Pattern (<i>Figures 2, 4</i>)	f = 32.5 MHz	35	55	mA
			f = 37.5 MHz	37	58	mA
I _{CCRZ}	Receiver Supply Current, Power Down	Power Down = Low		1	10	μA

Switching Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified

Symbol	Parameter	Min	Typ	Max	Units
LLHT	LVDS Low-to-High Transition Time (<i>Figure 3</i>)		0.75	1.5	ns
LHLT	LVDS High-to-Low Transition Time (<i>Figure 3</i>)		0.75	1.5	ns
CLHT	CMOS/TTL Low-to-High Transition Time (<i>Figure 4</i>)		3.5	6.5	ns
CHLT	CMOS/TTL High-to-Low Transition Time (<i>Figure 4</i>)		2.7	6.5	ns
TCIT	TxCLK IN Transition Time (<i>Figure 5</i>)			8	ns
TCCS	TxOUT Channel-to-Channel Skew (Note A) (<i>Figure 6</i>)			350	ps
TSSPW	Tx Sub-Symbol Pulse Width (<i>Figure 6</i>)	f = 20 MHz	5.5	7	8
RCCS	RxIN Channel-to-Channel Skew (Note B)			700	ps
TCIP	TxCLK IN Period (<i>Figure 7</i>)	25	T	50	ns
TCIH	TxCLK IN High Time (<i>Figure 7</i>)	0.35T	0.5T	0.65T	ns
TCIL	TxCLK IN Low Time (<i>Figure 7</i>)	0.35T	0.5T	0.65T	ns
TSTC	TxIN Setup to TxCLK IN (<i>Figure 7</i>)	8			ns
THTC	TxIN Hold to TxCLK IN (<i>Figure 7</i>)	2.5	2		ns
RCOP	RxCLK OUT Period (<i>Figure 8</i>)	25	T	50	ns

Note A: This limit based on bench characterization.

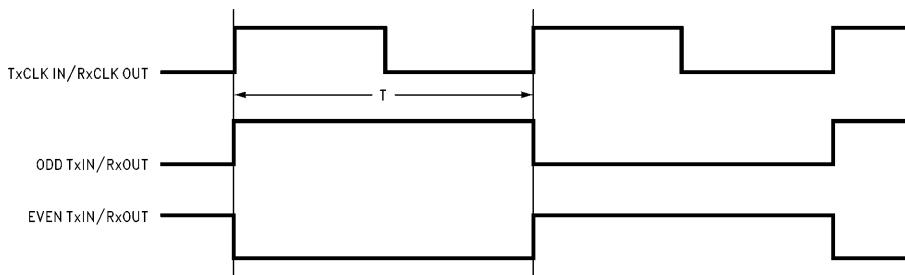
Note B: This limit assumes a maximum cable skew of 350 ps.

Switching Characteristics

Over recommended operating supply and temperature ranges unless otherwise specified (Continued)

Symbol	Parameter		Min	Typ	Max	Units
RCOH	RxCLK OUT High Time (<i>Figure 8</i>)	f = 20 MHz	21.5			ns
		f = 40 MHz	10.5			ns
RCOL	RxCLK OUT Low Time (<i>Figure 8</i>)	f = 20 MHz	19			ns
		f = 40 MHz	6			ns
RSRC	RxOUT Setup to RxCLK OUT (<i>Figure 8</i>)	f = 20 MHz	14			ns
		f = 40 MHz	4.5			ns
RHRC	RxOUT Hold to RxCLK OUT (<i>Figure 8</i>)	f = 20 MHz	16			ns
		f = 40 MHz	6.5			ns
TCCD	TxCLK IN to TxCLK OUT Delay @ 25°C, V _{CC} = 5.0V (<i>Figure 9</i>)		5		9.7	ns
RCCD	RxCLK IN to RxCLK OUT Delay @ 25°C, V _{CC} = 5.0V (<i>Figure 10</i>)		7.6		11.9	ns
TPLLS	Transmitter Phase Lock Loop Set (<i>Figure 11</i>)				10	ms
RPLLS	Receiver Phase Lock Loop Set (<i>Figure 12</i>)				10	ms

AC Timing Diagrams



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FIGURE 1. “Worst Case” Test Pattern

Device Pin Name	Signal	Signal Pattern	Signal Frequency
TxCLK IN/RxCLK OUT	Dot Clk	High frequency square wave	f
TxIN0/RxOUT0	R5	Low	f/16
TxIN1/RxOUT1	R4	Steady State, High	f/8
TxIN2/RxOUT2	R3	Low	f/4
TxIN3/RxOUT3	R2	High	f/2
TxIN4/RxOUT4	R1	Steady State, Low	
TxIN5/RxOUT5	R0	Steady State, Low	
TxIN6/RxOUT6	G5	Low	f/16
TxIN7/RxOUT7	G4	Low	f/8
TxIN8/RxOUT8	G3	Low	f/4
TxIN9/RxOUT9	G2	Low	f/2
TxIN10/RxOUT10	G1	Steady State, Low	
TxIN11/RxOUT11	G0	Steady State, Low	
TxIN12/RxOUT12	B5	Low	f/16
TxIN13/RxOUT13	B4	Low	f/8
TxIN14/RxOUT14	B3	Low	f/4
TxIN15/RxOUT15	B2	Low	f/2
TxIN16/RxOUT16	B1	Steady State, Low	
TxIN17/RxOUT17	B0	Steady State, Low	
TxIN18/RxOUT18	Sync1	Steady State, High	
TxIN19/RxOUT19	Sync2	Steady State, High	
TxIN20/RxOUT20	Sync3	Steady State, High	

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FIGURE 2. “16 Grayscale” Test Pattern

Note 1: The worst case test pattern produces a maximum toggling of device digital circuitry, LVDS I/O and TTL I/O.

Note 2: The 16 grayscale test pattern tests device power consumption for a “typical” LCD display pattern. The test pattern approximates signal switching needed to produce groups of 16 vertical stripes across the display.

Note 3: Figure 1 and Figure 2 show a falling edge data strobe (TxCLK IN/RxCLK OUT).

AC Timing Diagrams (Continued)

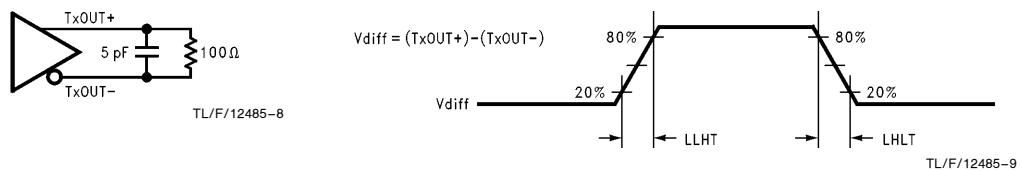


FIGURE 3. DS90CF561 (Transmitter) LVDS Output Load and Transition Timing

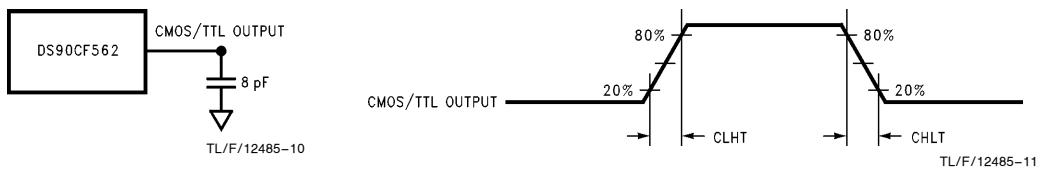


FIGURE 4. DS90CF562 (Receiver) CMOS/TTL Output Load and Transition Timing

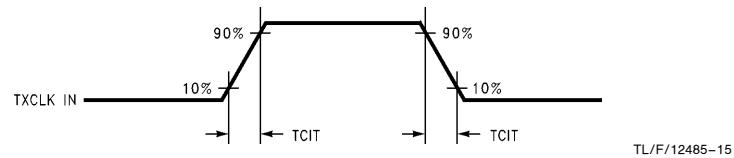


FIGURE 5. DS90CF561 (Transmitter) Input Clock Transition Time

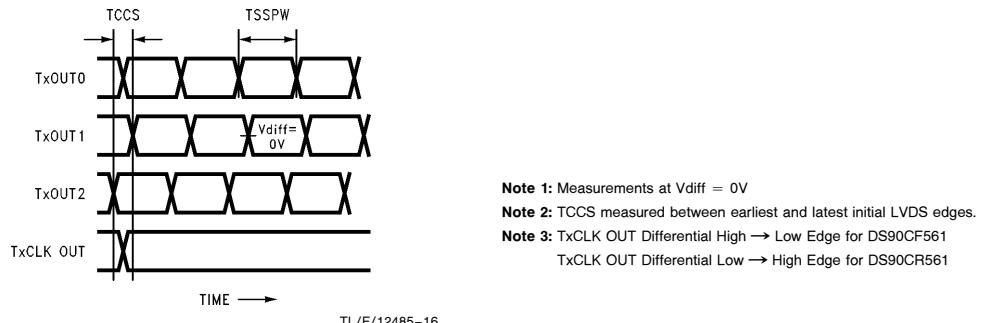
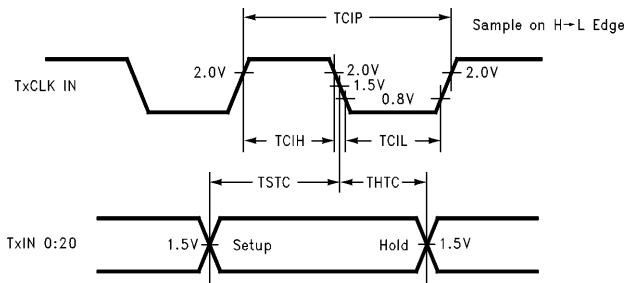


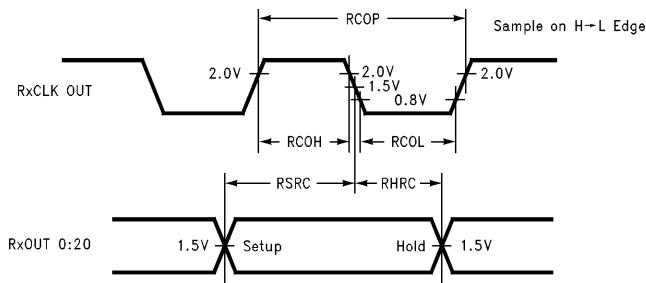
FIGURE 6. DS90CF561 (Transmitter) Channel-to-Channel Skew and Pulse Width

AC Timing Diagrams (Continued)



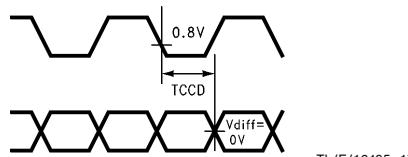
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FIGURE 7. DS90CF561 (Transmitter) Setup/Hold and High/Low Times



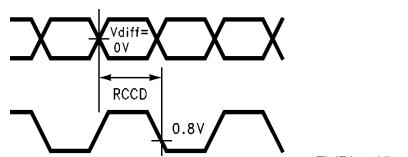
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FIGURE 8. DS90CF562 (Receiver) Setup/Hold and High/Low Times



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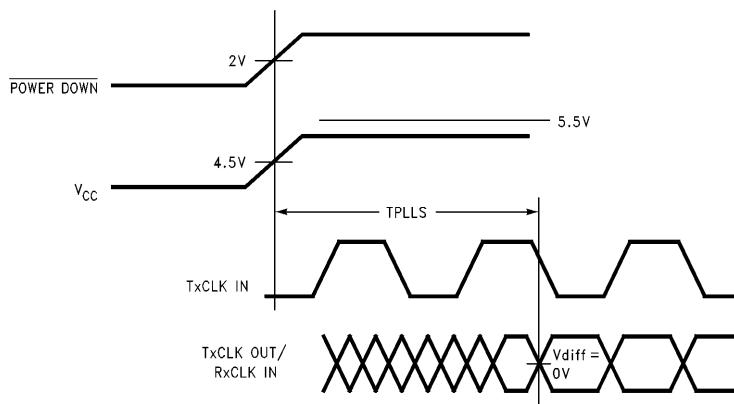
FIGURE 9. DS90CF561 (Transmitter) Clock In to Clock Out Delay



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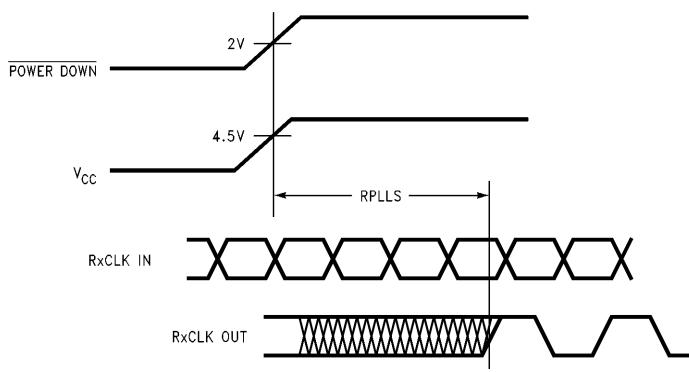
FIGURE 10. DS90CF562 (Receiver) Clock In to Clock Out Delay

AC Timing Diagrams (Continued)



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FIGURE 11. DS90CF561 (Transmitter) Phase Lock Loop Set Time



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FIGURE 12. DS90CF562 (Receiver) Phase Lock Loop Set Time

AC Timing Diagrams (Continued)

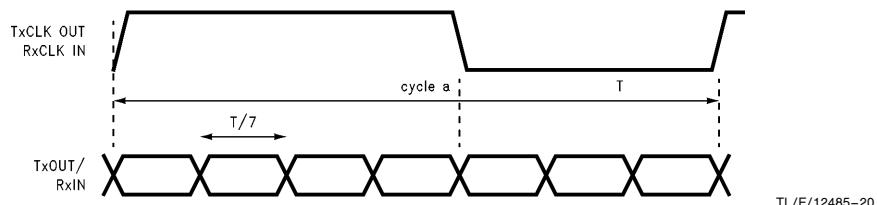


FIGURE 13. Seven Bits of LVDS in One Clock Cycle

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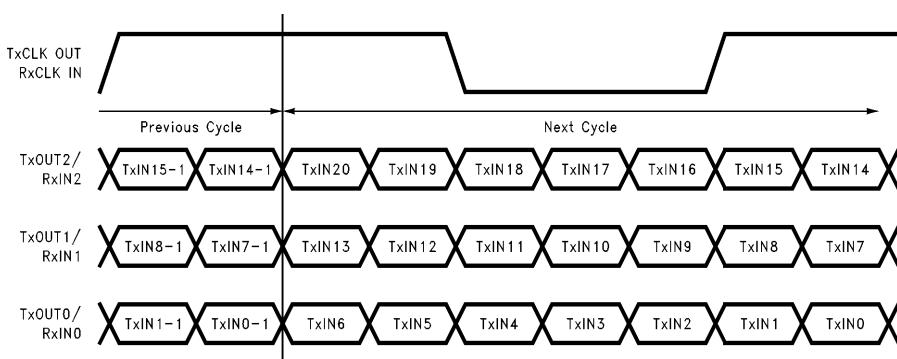


FIGURE 14. 21 Parallel TTL Data Inputs Mapped to LVDS Outputs (DS90CF561)

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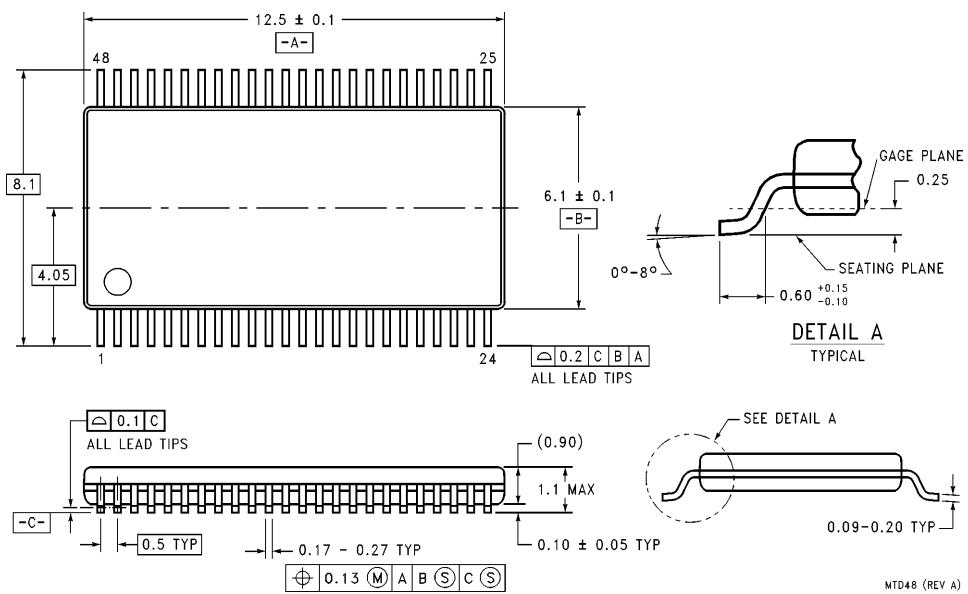
DS90CF561 Pin Description—FPD Link Transmitter

Pin Name	I/O	No.	Description
TxIN	I	21	TTL level input. This includes: 6 Red, 6 Green, 6 Blue, and 3 control lines (FPLINE, FPFRAME, DRDY). (Also referred to as HSYNC, VSYNC and DATA ENABLE.)
TxOUT +	O	3	Positive LVDS differential data output
TxOUT -	O	3	Negative LVDS differential data output
FPSHIFT IN	I	1	TTL level clock input. The falling edge acts as data strobe.
TxCLK OUT +	O	1	Positive LVDS differential clock output
TxCLK OUT -	O	1	Negative LVDS differential clock output
PWR DOWN	I	1	TTL level input. Assertion (low input) TRI-STATES the outputs, ensuring low current at power down.
V _{CC}	I	4	Power supply pins for TTL inputs
GND	I	5	Ground pins for TTL inputs
PLL V _{CC}	I	1	Power supply pin for PLL
PLL GND	I	2	Ground pins for PLL
LVDS V _{CC}	I	1	Power supply pin for LVDS outputs
LVDS GND	I	3	Ground pins for LVDS outputs

DS90CF562 Pin Description—FPD Link Receiver

Pin Name	I/O	No.	Description
RxIN +	I	3	Positive LVDS differential data inputs
RxIN -	I	3	Negative LVDS differential data inputs
RxOUT	O	21	TTL level data outputs. This includes: 6 Red, 6 Green, 6 Blue, and 3 control lines (FPLINE, FPFRAME, DRDY). (Also referred to as HSYNC, VSYNC and DATA ENABLE.)
RxCLK IN +	I	1	Positive LVDS differential clock input
RxCLK IN -	I	1	Negative LVDS differential clock input
FPSHIFT OUT	O	1	TTL level clock output. The falling edge acts as data strobe.
PWR DOWN	I	1	TTL level input. Assertion (low input) maintains the receiver outputs in the previous state
V _{CC}	I	4	Power supply pins for TTL outputs
GND	I	5	Ground pins for TTL outputs
PLL V _{CC}	I	1	Power supply for PLL
PLL GND	I	2	Ground pin for PLL
LVDS V _{CC}	I	1	Power supply pin for LVDS inputs
LVDS GND	I	3	Ground pins for LVDS inputs

Physical Dimensions (millimeters)



**48-Lead Molded Thin Shrink Small Outline Package, JEDEC
NS Package Number MTD48**

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 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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